

<b>Notice of References Cited</b>	Application/Control No. 10/029,160	Applicant(s)/Patent Under Reexamination EDENS ET AL.	
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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-			
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**FOREIGN PATENT DOCUMENTS**

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**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Becker et al., "The Masking Breakdown Point of Multivariate Outlier Identification Rules", September 1999, Journal of the American Statistical Association, 94, 447, 947 (9), ISSN: 0162-1459.
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